

Notice of References Cited	Application/Control No. 09/944,344	Applicant(s)/Patent Under Reexamination MATSUKI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,492,681	02-1996	Pasek et al.	423/32
*	B	US-4,677,234	06-1987	Bartley, William J.	568/864
*	C	US-6,218,335	04-2001	Okada et al.	502/340
*	D	US-5,449,845	09-1995	Fernandez et al.	570/177
*	E	US-4,659,555	04-1987	Gottfried et al.	423/419.1
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